

## Chapter 9 Hypothesis Testing

## 9.1 Introduction to Hypothesis Testing

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- **Problem:** Given a realization  $x_1, \dots, x_n$  of a random sample  $X_1, \dots, X_n$  from some population distribution  $f(x; \theta)$ , we want to know whether the true parameter  $\theta$  belongs to some specific subset  $\Theta_0$  of the parameter space  $\Theta$ .
- **Definition: Hypothesis.** A *hypothesis* is a statement about the population parameter. The two complementary hypotheses in a hypothesis testing problem are called the *null hypothesis* and the *alternative hypothesis*. They are denoted by  $H_0$  and  $H_1$ , respectively.
- **Remark:** The general formats of the null and alternative hypotheses are  $H_0 : \theta \in \Theta_0$  and  $H_1 : \theta \in \Theta_0^c$ , respectively.

## 9.1 Introduction to Hypothesis Testing

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- **Example:** If  $\theta$  denotes the average change in a patient's blood pressure after taking a drug. We might be interested in testing  $H_0 : \theta = 0$  versus  $H_1 : \theta \neq 0$ . The null hypothesis states that, on the average, the drug has no effect on blood pressure. The alternative hypothesis states that there is some effect.
- **Example:** If  $\theta$  denotes the proportion of defective items. We might be interested in testing  $H_0 : \theta \geq \theta_0$  versus  $H_1 : \theta < \theta_0$ , where  $\theta_0$  is the maximum acceptable proportion of defective items. The null hypothesis states that the proportion of defective items is unacceptably high.

## 9.1 Introduction to Hypothesis Testing

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- **Definition: Simple Hypothesis Versus Composite Hypothesis.**

A hypothesis is simple if and only if it contains exactly one population. If the hypothesis contains more than one population, it is called a composite hypothesis.

- **Definition: Hypothesis Testing.** A hypothesis testing procedure or a hypothesis test is a decide rule that specifies

- for what sample values  $\mathbf{x}^n$  the decision is made to accept  $\mathbb{H}_0$  as true, and
- for what sample values  $\mathbf{x}^n$   $\mathbb{H}_0$  is rejected and  $\mathbb{H}_A$  is accepted as true.

## 9.1 Introduction to Hypothesis Testing

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- **Definition: Critical Region or Rejection Region.** The set  $R$  of the sample points  $\mathbf{X}^n$  for which  $\mathbb{H}_0$  will be rejected is called the *rejection region* or *critical region*. The complement of the rejection region is called the *acceptance region*.
- **Remarks:**
  - The critical region  $C$  does not depend on the parameter  $\theta$ .
  - Critical region and acceptance region forms a partition of all possible values of  $\mathbf{x}_n$ .
  - A test is determined by its critical region.

## 9.1 Introduction to Hypothesis Testing

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- **Remarks:**

- If  $\theta \in \Theta_0$  ( $H_0$  holds) and the observation  $(x_1, \dots, x_n)$  falls into the critical region  $C$ , then a *type I error* is made. The probability of making type I error is

$$\alpha(\theta) = P_\theta[(X_1, \dots, X_n) \in C], \quad \theta \in \Theta_0.$$

- If  $\theta \in \Theta_0^c$  ( $H_1$  holds) and the observation  $(x_1, \dots, x_n)$  is in the acceptance region, then a *type II error* is made. The probability of making type II error is

$$\beta(\theta) = 1 - P_\theta[(X_1, \dots, X_n) \in C], \quad \theta \in \Theta_0^c.$$

- If the critical region  $C$  decreases, the probability of making type I error decreases, but the probability of making type II error increases. Similarly, if  $C$  increases,  $\beta(\theta)$  decreases, but  $\alpha(\theta)$  increases.

## 9.1 Introduction to Hypothesis Testing

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- **Definition: Power of Tests.** If  $R$  is the critical region of a test of the null hypothesis  $H_0 : \theta \in \Theta_0$ , the function  $\pi(\theta) = P_\theta(\mathbf{X}^n \in R)$  is called the *power* of test with the rejection region  $R$ .
- **Definition: Type I and Type II Errors.** If  $H_0 : \theta \in \Theta_0$  holds and the observation  $\mathbf{x}^n$  falls into the critical region  $R$ , then a Type I error is made. The probability of making Type I error is

$$\alpha(\theta) \equiv P_\theta(\mathbf{X}^n \in R | H_0).$$

If  $H_a : \theta \in \Theta_0^c$  holds and the observation  $\mathbf{x}^n$  is in the acceptance region, then a Type II error is made. The probability of making Type II error is

$$\beta(\theta) \equiv 1 - P_\theta(\mathbf{X}^n \in R | H_A).$$

## 9.1 Introduction to Hypothesis Testing

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- **Definition: Uniformly Most Powerful Tests.** Let  $\mathbb{C}$  be a class of tests for testing  $H_0 : \theta \in \Theta_0$  versus  $H_a : \theta \in \Theta_A$ . A test  $T(\mathbf{X}^n)$  in class  $\mathbb{C}$ , with power function  $\pi(\theta)$ , is a uniformly most powerful test over  $\mathbb{C}$  if  $\pi(\theta) \geq \tilde{\pi}(\theta)$  for all  $\theta \in \Theta_A$  and all  $\tilde{\pi}(\theta)$  that is a power function of any other test  $G(\mathbf{X}^n)$  in class  $\mathbb{C}$ .

- **Definition: Size of Tests.** The *size* of test  $C$  is defined as

$$\bar{\alpha}_C = \sup_{\theta \in \Theta_0} \pi_C(\theta).$$

For  $0 < \alpha \leq 1$ , a test  $C$  satisfying  $\bar{\alpha}_C \leq \alpha$  will be called an *level  $\alpha$  test*.  $\alpha$  is called the *significance level*.



## 9.2 Neyman-Pearson Lemma

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- **Theorem: Neyman-Pearson Lemma.** Let  $\mathbf{x}_n = (x_1, \dots, x_n)$  be an observation from distribution with joint PMF/PDF  $f(\mathbf{x}_n; \theta)$ . Consider testing a **simple** null hypothesis  $H_0 : \theta = \theta_0$  versus a **simple** alternative  $H_1 : \theta = \theta_1$ . Suppose a test with rejection and acceptance regions  $\mathbb{R}_n(c)$  and  $\mathbb{A}_n(c)$  defined as follows

$$\mathbb{R}_n(c) = \left\{ \mathbf{x}^n : \frac{f_{\mathbf{X}^n}(\mathbf{x}^n, \theta_1)}{f_{\mathbf{X}^n}(\mathbf{x}^n, \theta_0)} > c \right\}$$

and

$$\mathbb{A}_n(c) = \left\{ \mathbf{x}^n : \frac{f_{\mathbf{X}^n}(\mathbf{x}^n, \theta_1)}{f_{\mathbf{X}^n}(\mathbf{x}^n, \theta_0)} \leq c \right\}$$

for some  $c \geq 0$ , and

$$P[\mathbf{X}^n \in \mathbb{R}_n(c) | H_0] = \alpha.$$

## 9.2 Neyman-Pearson Lemma

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- Then

- (1) [**Sufficiency**] Any test that satisfies the above conditions is a uniformly most powerful level  $\alpha$  test.
- (2) [**Necessity**] If there exists a test satisfying the above conditions with  $c > 0$ , then every uniformly most powerful level  $\alpha$  test is a size  $\alpha$ , and every uniformly most powerful level  $\alpha$  test satisfies the first two conditions except perhaps on a set  $A$  satisfying  $P(\mathbf{X}^n \in A|H_0) = P(\mathbf{X}^n \in A|H_A) = 0$ .

## 9.2 Neyman-Pearson Lemma

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- **Remarks:**

- $f(\mathbf{X}_n; \theta_1)/f(\mathbf{X}_n; \theta_0)$  is called the *likelihood ratio statistic*.
- The test  $C = \{\mathbf{x}_n : f(\mathbf{x}_n; \theta_1)/f(\mathbf{x}_n; \theta_0) \geq k\}$  is called the *likelihood ratio test*.
- By Neyman-Pearson lemma, we want the likelihood ratio to be as large as possible in the critical region.

## 9.2 Neyman-Pearson Lemma

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- **Corollary.** Suppose  $T(\mathbf{X}^n)$  is a sufficient statistic for  $\theta$  and  $g(t, \theta_i)$  is the PMF/PDF of  $T(\mathbf{X}^n)$  corresponding to  $\theta_i, i = 0, 1$ . Then any test based on  $T(\mathbf{X}^n)$  with rejection region  $\mathbb{R}_n$  is a uniformly most powerful level  $\alpha$  test for  $\mathbb{H}_0 : \theta = \theta_0$  against  $\mathbb{H}_A : \theta = \theta_1$  if the test has the rejection and acceptance regions

$$\mathbb{R}_n(c) = \left\{ t : \frac{g(t, \theta_1)}{g(t, \theta_0)} > c \right\}$$

and

$$\mathbb{A}_n(c) = \left\{ t : \frac{g(t, \theta_1)}{g(t, \theta_0)} \leq c \right\}$$

for some  $c \geq 0$ , where  $P[T(\mathbf{X}^n) \in \mathbb{R}_n(c) | \mathbb{H}_0] = \alpha$ .

## 9.2 Neyman-Pearson Lemma

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- **Example:** Suppose random variables  $X_1, \dots, X_n$  are i.i.d. from the EXP( $\lambda$ ) distribution with pdf  $f(x; \lambda) = \lambda e^{-\lambda x}$  ( $E(X_i) = 1/\lambda$ ). Test hypothesis  $H_0 : \lambda = 5$  against  $H_1 : \lambda = 8$  at the significance level  $\alpha$ .

– The likelihood ratio is

$$\frac{f(\mathbf{x}_n; \lambda = 8)}{f(\mathbf{x}_n; \lambda = 5)} = \frac{\prod_{i=1}^n 8e^{-8x_i}}{\prod_{i=1}^n 5e^{-5x_i}} = \left(\frac{8}{5}\right)^n e^{-3\sum_{i=1}^n x_i}.$$

- The most powerful test has the form of  $\{\frac{f(\mathbf{x}_n; \lambda=8)}{f(\mathbf{x}_n; \lambda=5)} > k\}$ , which is equivalent to  $\{\sum_{i=1}^n x_i < k^*\}$ .
- Find  $k^*$  such that  $P_{\lambda=5}(\sum_{i=1}^n X_i < k^*) = \alpha$ , where  $2\lambda \sum_{i=1}^n X_i$  follows a  $\chi_{2n}^2$  distribution. If  $n = 10$ ,  $\alpha = 0.1$ , then we can obtain  $k^* = 1.244$  (0.1-quantile of  $\chi_{20}^2$  is 12.44).
- $\{\sum_{i=1}^n x_i < k^*\}$  is the most powerful test at significant level  $\alpha$ .
- The probability of making type II error is 0.4637.

## 9.2 Neyman-Pearson Lemma

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- **Remarks:**

- Here  $\sum_{i=1}^n X_i$  is called a *test statistic*, and  $k^*$  is called the *critical value*.
- In this example, if we observed a realization  $(x_1, \dots, x_n)$ ,  $P_{\lambda=5}(\sum_{i=1}^n X_i < \sum_{i=1}^n x_i)$  is called the *p-value* of the observation.
- The *p* value is the probability of obtaining a test statistic at least as extreme as the one that was observed.  $H_0$  will be accepted if *p* value of the observation is larger than  $\alpha$ ,  $H_0$  will be rejected if *p* value of the observation is less than  $\alpha$ .
- In this example, consider testing  $H_0 : \lambda = 8$  against  $H_1 : \lambda = 5$ . The most powerful critical region at significance level  $\alpha = 0.1$  is  $\{\sum_{i=1}^n x_i > 1.7757\}$ . It is possible to find some observations that are accepted by both  $H_0 : \lambda = 5$  and  $H_0 : \lambda = 8$  at significance level  $\alpha = 0.1$ .

## 9.2 Neyman-Pearson Lemma

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- **Example:** Suppose  $X_1, \dots, X_n$  are i.i.d. from normal distribution  $N(\mu, \sigma^2)$  with  $\sigma^2$  known. Consider testing  $H_0 : \mu = 0$  against  $H_1 : \mu > 0$  at significance level  $\alpha$ .

- For any fixed  $\mu' > 0$ , consider the likelihood ratio test for  $H_0 : \mu = 0$  against  $H_1 : \mu = \mu'$ .

- We have

$$\frac{f(\mathbf{x}_n; \mu = \mu')}{f(\mathbf{x}_n; \mu = 0)} \propto \exp \left\{ (\mu'/\sigma^2) \sum_{i=1}^n x_i \right\}.$$

- Because  $\mu' > 0$ , the most powerful test has the form of  $\{\sum_{i=1}^n x_i > k\}$ .

- Find  $k^*$  such that  $P_{\mu=0}(\sum_{i=1}^n X_i > k^*) = \alpha$ , where  $\frac{1}{\sqrt{n}\sigma} \sum_{i=1}^n X_i$  follows a standard normal distribution.

- Because the critical regions (or  $k^*$ ) are the same for all  $\mu' > 0$ ,  $C = \{\sum_{i=1}^n X_i > k^*\}$  is the UMP test at significant level  $\alpha$ .

## 9.2 Neyman-Pearson Lemma

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- **Example:** Suppose  $X_1, \dots, X_n$  are i.i.d. from normal distribution  $N(\mu, \sigma^2)$  with  $\sigma^2$  known. Consider testing  $H_0 : \mu = 0$  against  $H_1 : \mu \neq 0$  at significance level  $\alpha$ .
  - Fixed  $\mu' \neq 0$ , consider the likelihood ratio test for  $H_0 : \mu = 0$  against  $H_1 : \mu = \mu'$ .
  - The critical regions obtained by using the likelihood ratio test are  $\{\sum_{i=1}^n X_i > k^*\}$  and  $\{\sum_{i=1}^n X_i < k^*\}$  for cases  $\mu' > 0$  and  $\mu' < 0$ , respectively. The critical regions are different for different  $\mu'$ . The UMP test does not exist in this case.
  - We can use  $\{|\frac{1}{\sqrt{n}\sigma} \sum_{i=1}^n X_i| > k^*\}$ , where  $k^* > 0$  is the value that makes  $P_{\mu=0}(|\frac{1}{\sqrt{n}\sigma} \sum_{i=1}^n X_i| > k^*) = \alpha$ .
  - However,  $\{|\frac{1}{\sqrt{n}\sigma} \sum_{i=1}^n X_i| > k^*\}$  is not a UMP test.



## 9.3 Wald Test and Lagrangian Multiplier Test

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**Wald Test:** Consider testing

$$H_0 : g(\theta) = 0 \quad \text{against} \quad H_1 : g(\theta) \neq 0.$$

$$H_0 : g(\theta_0) = 0 \quad \text{against} \quad H_1 : g(\theta_0) \neq 0.$$

- **Assumptions:**

- **B.1:**  $\sqrt{n}(\hat{\theta}_n - \theta_0) \xrightarrow{d} N(0, V)$ , where  $V$  is a  $p \times p$  symmetric bounded and non-singular covariance matrix,  $\theta_0$  is the true parameter value which is an interior point in  $\Theta$ , and  $\Theta$  is a compact parameter space.
- **B.2:**  $\hat{V}_n \xrightarrow{p} V$ , where  $\hat{V}_n$  is a function of  $X_1, \dots, X_n$ .
- **B.3:**  $g : \mathbb{R}^p \rightarrow \mathbb{R}^q$  ( $q \leq p$ ) is a continuously differentiable vector-valued function of  $\theta$ . The first derivative  $G(\theta_0) \triangleq \frac{\partial}{\partial \theta} g(\theta_0)$  is a  $q \times p$  matrix and has rank  $q$ .

- **Remark:**  $\hat{\theta}_n$  can be the MLE or MME.

## 9.3 Wald Test and Lagrangian Multiplier Test

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- **Theorem: Asymptotic Distribution of Wald Test Statistic.**

Suppose Assumptions **B.1-B.3** hold. Under  $H_0$ ,

$$\widehat{W}_n \triangleq ng(\widehat{\theta}_n)' \left[ G(\widehat{\theta}_n) \widehat{V}_n G(\widehat{\theta}_n)' \right]^{-1} g(\widehat{\theta}_n) \xrightarrow{d} \chi_q^2.$$

- **Remarks:**

- In Wald test, we only need to consider parameter estimation in the whole parameter space  $\Theta$ .
- Test  $C = \{\mathbf{x}_n : \widehat{W}_n > \chi_{\alpha,q}^2\}$  is an asymptotically level  $\alpha$  test, where  $\chi_{\alpha,q}^2$  is the upper  $\alpha$ -quantile of  $\chi_q^2$  distribution..

## 9.3 Wald Test and Lagrangian Multiplier Test

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### Lagrangian Multiplier Test:

- Consider maximizing the normalized log-likelihood  $l(\theta) = \frac{1}{n} \sum_{i=1}^n \log f(X_i; \theta)$  under  $H_0 : g(\theta) = 0$ .
- The Lagrangian function is

$$L(\theta; \lambda) = l(\theta) + \lambda' g(\theta),$$

where  $\lambda$  is a  $q \times 1$  vector.

- $\tilde{\theta}_n$  and  $\tilde{\lambda}_n$  are the solutions of the first order conditions

$$\begin{aligned} \frac{\partial L(\tilde{\theta}_n, \tilde{\lambda}_n)}{\partial \theta} &= \frac{\partial l(\tilde{\theta}_n)}{\partial \theta} + \tilde{\lambda}_n' G(\tilde{\theta}_n) = 0, \\ \frac{\partial L(\tilde{\theta}_n, \tilde{\lambda}_n)}{\partial \lambda} &= g(\tilde{\theta}_n) = 0. \end{aligned}$$

## 9.3 Wald Test and Lagrangian Multiplier Test

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- **Theorem: Asymptotic Distribution of Lagrangian Multiplier Test Statistic.** Suppose Assumptions **A.1-A.6** hold, and Assumption B.3 holds. Under  $H_0$ ,

$$LM \triangleq -n\tilde{\lambda}'_n G(\tilde{\theta}_n) \left[ \hat{H}(\tilde{\theta}_n) \right]^{-1} G(\tilde{\theta}_n)' \tilde{\lambda}_n \xrightarrow{d} \chi^2_q,$$

- **Remarks:**

- An asymptotically size  $\alpha$  LM test will reject the null hypothesis  $\mathbb{H}_0 : g(\theta_0) = 0$  when LM exceeds the  $(1 - \alpha)$ th quantile of the  $\chi^2$  distribution.
- In Lagrangian multiplier test, we only need to maximize the likelihood function in the null parameter space  $\Theta_0 = \{\theta : g(\theta) = 0\}$ .
- Test  $C = \{\mathbf{x}_n : LM_n > \chi^2_{\alpha, q}\}$  is an asymptotically level  $\alpha$  test.
- In many cases, Wald test and Lagrangian multiplier test are not as powerful as the generalized likelihood ratio test.

## 9.4 The Likelihood Ratio Test

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- **Likelihood Ratio(LR) Test.** Consider a LR test for  $\mathbb{H}_0 : g(\theta) = 0$ . Suppose  $\mathbf{X}^n$  is an IID random sample from the population  $f(x, \theta_0)$ , where  $\theta_0$  is an unknown parameter value in  $\Theta$ . Then the likelihood function of  $\mathbf{X}^n$  is

$$f_{\mathbf{X}^n}(\mathbf{X}^n, \theta) = \prod_{i=1}^n f(X_i, \theta).$$

The likelihood ratio statistic is defined as

$$\hat{\Lambda} = \frac{\max_{\theta \in \Theta} f_{\mathbf{X}^n}(\mathbf{X}^n, \theta)}{\max_{\theta \in \Theta_0} f_{\mathbf{X}^n}(\mathbf{X}^n, \theta)} = \frac{\prod_{i=1}^n f(X_i, \hat{\theta}_n)}{\prod_{i=1}^n f(X_i, \tilde{\theta}_n)},$$

where  $\hat{\theta}_n$  and  $\tilde{\theta}_n$  are the unconstrained and constrained MLE estimators respectively, that is  $\hat{\theta}_n = \arg \max_{\theta \in \Theta} \hat{l}(\theta)$ , and  $\tilde{\theta}_n = \arg \max_{\theta \in \Theta_0} \hat{l}(\theta)$ , with  $\hat{l}(\theta) = \frac{1}{n} \sum_{i=1}^n \ln f(X_i, \theta)$ . And  $\Theta_0$  is the parameter space  $\Theta$  subject to the constraint  $g(\theta) = 0$ .

## 9.4 Likelihood Ratio Test

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- **Example:** Suppose  $X_1, \dots, X_n$  are i.i.d. from normal distribution  $N(\mu, \sigma^2)$ .

Consider testing  $H_0 : \mu = 0$  against  $H_1 : \mu \neq 0$ . Find the likelihood ratio test (1) when  $\sigma^2$  is known; (2) when  $\sigma^2$  is unknown.

- (1) When  $\sigma^2$  is known,

$$\begin{aligned}\lambda(\mathbf{x}_n) &= \exp \left\{ -\frac{1}{2\sigma^2} \sum_{i=1}^n (x_i - \bar{x}_n)^2 + \frac{1}{2\sigma^2} \sum_{i=1}^n x_i^2 \right\} \\ &= \exp \left\{ -\frac{1}{2\sigma^2} \left( \sum_{i=1}^n x_i^2 - n\bar{x}_n^2 \right) + \frac{1}{2\sigma^2} \sum_{i=1}^n x_i^2 \right\} \\ &= \exp \left\{ \frac{n}{2\sigma^2} \bar{x}_n^2 \right\},\end{aligned}$$

the corresponding GLR test is  $\{\mathbf{x}_n : \lambda(\mathbf{x}_n) > k\}$ , which is equivalent to  $\{\mathbf{x}_n : |\frac{\sqrt{n}}{\sigma} \bar{x}_n| > k^*\}$ . Under  $H_0$ , the test statistic  $\frac{\sqrt{n}}{\sigma} \bar{X}_n$  follows a  $N(0, 1)$  distribution.

## 9.4 Likelihood Ratio Tests

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- (2) When  $\sigma^2$  is unknown,

$$\begin{aligned}\sup_{\mu, \sigma^2} f(\mathbf{x}_n; \mu, \sigma^2) &= \left[ \frac{n}{2\pi \sum_{i=1}^n (x_i - \bar{x}_n)^2} \right]^{n/2} e^{-n/2}, \\ \sup_{\mu=0, \sigma^2} f(\mathbf{x}_n; \mu, \sigma^2) &= \left[ \frac{n}{2\pi \sum_{i=1}^n x_i^2} \right]^{n/2} e^{-n/2},\end{aligned}$$

we have

$$\begin{aligned}\lambda(\mathbf{x}_n) &= \left[ \frac{\sum_{i=1}^n x_i^2}{\sum_{i=1}^n (x_i - \bar{x}_n)^2} \right]^{n/2} \\ &= \left[ 1 + \frac{n\bar{x}_n^2}{\sum_{i=1}^n (x_i - \bar{x}_n)^2} \right]^{n/2}.\end{aligned}$$

The corresponding GLR test is  $\left\{ \mathbf{x}_n : \frac{\sqrt{n(n-1)}|\bar{x}_n|}{\sqrt{\sum_{i=1}^n (x_i - \bar{x}_n)^2}} > k \right\}$ . Under  $H_0$ ,

the test statistic  $\frac{\sqrt{n(n-1)}\bar{X}_n}{\sqrt{\sum_{i=1}^n (X_i - \bar{X}_n)^2}}$  follows a  $t_{n-1}$  distribution.

## 9.4 Likelihood Ratio Test

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- **Theorem: LR Test.** Suppose Assumptions **A.1-A.6**, and **B.3** hold.

Consider testing

$$H_0 : g(\theta_0) = 0 \quad \text{against} \quad H_1 : g(\theta_0) \neq 0.$$

Under  $H_0$ ,

$$LR \triangleq 2 \ln \hat{\Lambda} = 2n \left[ \hat{l}_n(\hat{\theta}_n) - \hat{l}_n(\tilde{\theta}_n) \right] \xrightarrow{d} \chi_q^2.$$

- **Remarks:**

- GLR test statistic is a function of any sufficient statistic  $T$ .
- To construct an asymptotically level  $\alpha$  test, we can let critical region  $C = \{\mathbf{x}_n : 2 \log \lambda(\mathbf{x}_n) > \chi_{\alpha,q}^2\}$ , where  $\chi_{\alpha,q}^2$  is the upper  $\alpha$ -quantile of  $\chi_q^2$  distribution.
- We can show that if  $g(\theta_0) \neq 0$  ( $H_1$  holds), the power function of  $C = \{\mathbf{x}_n : 2 \log \lambda(\mathbf{x}_n) > \chi_{\alpha,q}^2\}$  at  $\theta_0$  tends to 1 as  $n \rightarrow \infty$ .



## 9.4 Likelihood Ratio Test

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- **Theorem.** If  $T(\mathbf{X}^n)$  is a sufficient statistic for  $\theta$ , and  $LR(\mathbf{X}^n)$  and  $LR[T(\mathbf{X}^n)]$  are the likelihood ratio based on  $\mathbf{X}^n$  and  $T(\mathbf{X}^n)$  respectively, then

$$LR(\mathbf{X}^n) = LR[T(\mathbf{X}^n)].$$

- **Examples.**
- **Conclusion.**